SCLS141C - DECEMBER 1982 - REVISED JULY 1998

- Eight D-Type Flip-Flops in a Single Package
- High-Current 3-State True Outputs Can Drive up to 15 LSTTL Loads
- Full Parallel Access for Loading
- Package Options Include Plastic Shrink Small-Outline (DB), Small-Outline (DW), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

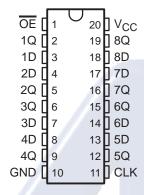
description

These 8-bit flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

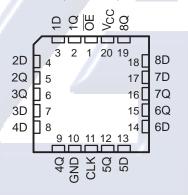
The eight flip-flops of the 'HC374 devices are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels that were set up at the data (D) inputs.

An output-enable (\overline{OE}) input places the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load

SN54HC374 . . . J OR W PACKAGE SN74HC374 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54HC374 . . . FK PACKAGE (TOP VIEW)



nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect the internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54HC374 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC374 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each flip-flop)

	-		
	INPUTS	OUTPUT	
OE	CLK	D	Q
L	\uparrow	Н	Н
L	\uparrow	L	L
L	H or L	Χ	Q ₀
Н	X	Χ	Z



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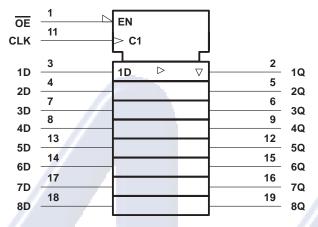
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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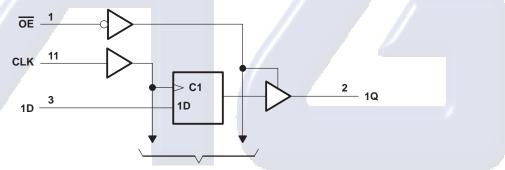
SCLS141C - DECEMBER 1982 - REVISED JULY 1998

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}		0.	5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see	Note 1)		. ±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	(see Note 1)	5. /.0	. ±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$.			. ±35 mA
Continuous current through V _{CC} or GND			. ±70 mA
Package thermal impedance, θ_{JA} (see Note 2): [DB package		115°C/W
	DW package		. 97°C/W
1	N package		. 67°C/W
F	PW package		128°C/W
Storage temperature range, T _{stg}		−65°C	to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



SN54HC374, SN74HC374 OCTAL EDGE-TRIGGERED D-TYPE FLIP-FLOPS WITH 3-STATE OUTPUTS SCLS141C - DECEMBER 1982 - REVISED JULY 1998

recommended operating conditions (see Note 3)

			SI	SN54HC374		18	UNIT		
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		2	5	6	2	5	6	V
		V _{CC} = 2 V	1.5			1.5			
ViH	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V
		V _{CC} = 6 V	4.2			4.2			
	Low-level input voltage	V _{CC} = 2 V	0		0.5	0		0.5	
VIL		V _{CC} = 4.5 V	0		1.35	0		1.35	V
		V _{CC} = 6 V	0		1.8	0		1.8	
VI	Input voltage		0		VCC	0		VCC	V
Vo	Output voltage		0		VCC	0	A	VCC	V
		V _{CC} = 2 V	0		1000	0		1000	
t _t	Input transition (rise and fall) time	$V_{CC} = 4.5 \text{ V}$	0	7/	500	0		500	ns
		$V_{CC} = 6 V$	0	7/	400	0		400	
TA	Operating free-air temperature		-55	/	125	-40		85	°C

NOTE 3: All unused inputs of the device must be held at VCC or GND to ensure proper device operation. Refer to the TI application report Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Vaa	// T	A = 25°C		SN54H	C374	SN74H	C374	UNIT
PARAMETER	TEST CO	NDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		I _{OH} = -6 mA	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	V _I = V _{IH} or V _{IL}	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	
27.7			4.5 V	ri ny	0.001	0.1		0.1	er e	0.1	
VOL		TATA	6 V		0.001	0.1		0.1		0.1	V
187,842		I _{OL} = 6 mA	4.5 V		0.17_	0.26		0.4		0.33	0.33
		I _{OL} = 7.8 mA	6 V	7 41	0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
loz	$V_O = V_{CC}$ or 0		6 V		±0.01	±0.5		±10		±5	μΑ
Icc	$V_I = V_{CC}$ or 0,	I _O = 0	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF

SCLS141C - DECEMBER 1982 - REVISED JULY 1998

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

		V	T _A = 25°C		SN54HC374		SN74HC374		UNIT
		VCC	MIN	MAX	MIN	MAX	MIN	MAX	UNII
		2 V		6		4		5	
fclock	Clock frequency	4.5 V		30		20		24	MHz
		6 V		35		24	11	28	
		2 V	80		120		100		
t _W	Pulse duration, CLK high or low	4.5 V	16		24		20		ns
		6 V	14		20	-//	17		
		2 V	100		150	//	125		ns
t _{su}	Setup time, data before CLK↑	4.5 V	20		30	/	25		
		6 V	17		25		21		
	Hold time, data after CLK↑	2 V	10		13		12		
th		4.5 V	5		5		5		ns
			5		5		5		

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	_A = 25°C	;	SN54H	IC374	SN74H	IC374	UNIT
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	6	12		4		5		
f _{max}			4.5 V	30	60		20		24		MHz
			6 V	35	70		24		28		
			2 V		63	180		270		225	
tpd	CLK	Any Q	4.5 V		17	36		54		45	ns
			6 V		15	31		46		38	
			2 V		60	150		225		190	
t _{en}	ŌĒ	Any Q	4.5 V		16	30		45		38	ns
17.7	-	7	6 V		14	26		38		32	7
141	and to		2 V	ĺ	36	150		225		190	7
^t dis	Œ	Any Q	4.5 V		17	30		45	ľ	38	ns
		ì	6 V)	16	26		38		32	
			2 V		28	60		90		75	
t _t		Any Q	4.5 V		8	12		18		15	ns
			6 V		6	10		15		13	

SCLS141C - DECEMBER 1982 - REVISED JULY 1998

switching characteristics over recommended operating free-air temperature range, $C_L = 150 \text{ pF}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	λ = 25°C	;	SN54H	IC374	SN74H	C374	UNIT
PARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	6	12				5		
f _{max}			4.5 V	30	60				24		MHz
			6 V	35	70				28		
		2 V		80	230		345		290		
t _{pd}	CLK	Any Q	4.5 V		22	46		69		58	ns
			6 V		19	39		58		49	
		Any Q	2 V		70	200		300		250	
t _{en}	ŌĒ		4.5 V		25	40	7/	60	_	50	ns
			6 V		22	34	1	51		43	
			2 V		45	210		315		265	
t _t		Any Q	4.5 V		17	42		63		53	ns
			6 V		13	36		53		45	

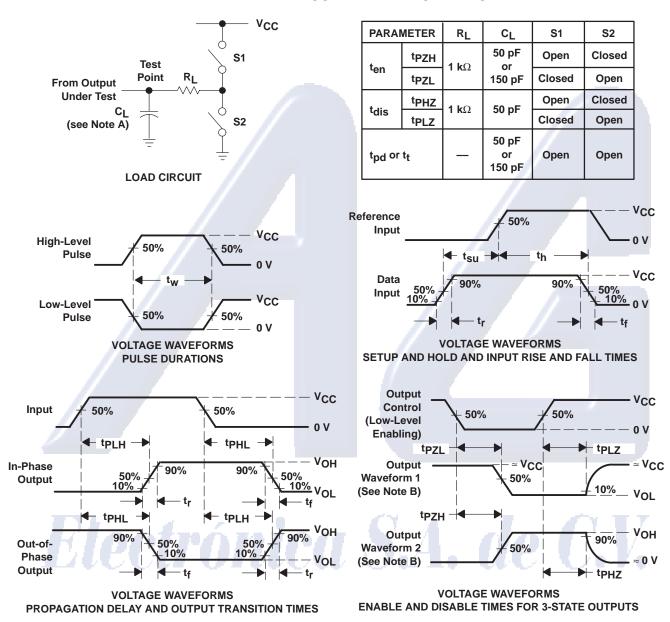
operating characteristics, $T_A = 25^{\circ}C$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance per flip-flop	No load	100	pF

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SCLS141C - DECEMBER 1982 - REVISED JULY 1998

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns.
- D. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
- E. The outputs are measured one at a time with one input transition per measurement.
- F. tpLZ and tpHZ are the same as tdis.
- G. tpZL and tpZH are the same as ten.
- H. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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